

ASU-PTL Photovoltaic Module Qualification

Type Test Certificate C1-GEE07004a is awarded to

Manufacturer: GE Energy

Type: GEPVc-175-M

Models: GEPVc-190-M, GEPVc-185-M, GEPVc-180-M, GEPVc-175-M, GEPVc-170-M, GEPVc-165-M, GEPVc-160-M

Specifications: 72 monocrystalline silicon Motech cells, Tyco (# M2107) j-box, EVA encapsulant, TPE backsheet, tempered glass superstrate, and anodized aluminum frame. Max system voltage is 1000 V. (See photos on back.)

Tested type: GEPVc-175-M Sampling: Nine manufacturer-supplied unconditioned test samples

Test samples received: 6/18/07

Tests conducted from: 6/27/07 To: 12/4/07

Tests conducted at: PTL, 7349 E. Unity Avenue, Mesa, Arizona, 85212 Web: www.poly.asu.edu/ptl

Manufacturer's Address: GE Energy LLC, 231 Lake Drive, Newark, DE 19702, USA

Test data and analysis detailed in Test Reports: R-GEE07004a PTL Project: GEE07004a

Certificate Issue Date: December 13, 2007



Testing Cert #0921.01
Since 6/23/97

The **Arizona State University Photovoltaic Testing Laboratory (ASU-PTL)** acknowledges that the above photovoltaic test samples have satisfied the requirements of the following test standard(s):

1. IEC 61215: Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval [2005-04].

The GEPVc-175-M qualified by similarity to the GEPV-85-M (project GEE06002) and the GEPVp-200-M (project GEE05013) based upon IEC Retest Guidelines [12/30/04]. Models listed above qualified based upon IEC Retest Guidelines [12/30/04] and IEC/TC82/WG2 Type and Model Conventions [4/16/02].

All tests in the above listed test standard(s) are within the ASU-PTL's scope of accreditation. Exception(s): None
Deviations from, additions to, or exclusions from aforementioned test standard(s): None

This test certificate may be used by the manufacturing company for its own purposes. However, the ASU-PTL cannot accept any legal responsibility from such use.

This test certificate pertains only to the modules tested at the date of test and does not guarantee any past or future performance.

If the tested type undergoes any future product or process modifications, limited re-testing is required to maintain valid certification according to the applicable Retest Guidelines.

G. Tamizhmani

Dr. Govindasamy Tamizh-Mani, Director
Certifying Authority

Joseph M. Kuitche

Joseph M. Kuitche, Operations Manager
Certifying Witness

Bo Li

Bo Li, Test Manager
Certifying Witness